Docket: 0756-2321

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re New Patent Application of		)	
Masaaki HIROKI		)	
Japanese Priority Application No. 2000-168143		) Attn: Applications	
Japanese Priority Date: June 5, 2000		)	Branch
For:	DEVICE FOR INSPECTING ELEMENT	)	
	SUBSTRATES AND METHOD OF	)	
	INSPECTION USING THIS DEVICE	) Date	e: May 30, 2001

## PRELIMINARY AMENDMENT

Honorable Commissioner for Patents

Washington, D.C. 20231

Sir:

Please preliminarily amend the subject application as follows:

## **IN THE SPECIFICATION:**

Please amend the specification as follows: -Please note that the specification is presented below in its amended form. It is further presented as an Attachment to the Amendment whereby the amendments to the specification are outlined using the conventional method of bracketing and underlining.

Page 11, under the heading BRIEF DESCRIPTION OF THE DRAWINGS, please amend paragraphs one and two as follows:

Figs. 1 (A), 1(B), and 1(C) are diagrams illustrating an inspection device of this invention;

